Advances in Artificial Intelligence, Machine Learning and Deep Learning Application

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Message from the Guest Editors

The purpose of this Special Issue is to report on the advances in state-of-the-art research on artificial intelligence and machine learning applications. This includes the design and development of novel algorithms based on machine learning and deep learning for application to data acquired from recently emerged devices, sensors, and equipment for the automatic prediction and detection of patterns of interest. This also includes implementation of novel AI and big data technologies for extracting relevant information from unstructured data with enhanced performance across different sectors. The advances in the state-of-the-art for addressing real-world AI applications are of great interest.

The research domains may involve (but are not limited to):

- Medical diagnosis
- Personalized health monitoring and management
- Assistive technologies
- Clinical engineering
- Health technology assessment
- Robotics
- Agricultural technologies
- Autonomous vehicular technologies
- Intelligence led policing
- Industrial manufacturing

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SpecialIssue

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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